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'Unique ciusion designation number. 'See attached Kinds of U.S. Patent Documents. 'Enter Office that Issued the document, by the two-letter cide (WIPO Standard ST.3). 'Fof Japanese patent documents, the indication of the year of the reign of the Emperor must precede the terial number of the patent document. 'Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 'Applicant is to place a check mark here if English language Translation is attached.





Form PTO-1449 (Modified) Atty Docket N .: Serial No.: 09/295,269 03401.P002D7D1 JUL 1 7 2002 2 List of Patents and Publications Statement Applicant: Igor Y. Khandros (Use several sheets I may sarv) Page 2 of 5 Filing Date: April 20, 1999 REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS** Examiner Document No. Class Sub-Filing date Initials Class if appropriate AA 5,066,907 Tarzwell et al. 324 158 2/6/90 AB 5,095,187 Gliga 219 68 12/20/89 AC 5,123,850 Elder et al. 439 67 6/7/91 AD 5,136,367 Chlu 357 74 8/31/90 ΑE 4,918,032 Jain et al. 437 228 7/8/88 AF 4,998,885 Beaman 439 66 10/27/89 AG 4,705,205 Allen et al. 228 180 5/14/84 AH 4,724,383 Hart 324 158 F 5/3/85 Αl 4,732,313 Kobayashi et al. 228 179 7/26/85 4,751,199 Phy 437 209 1/21/87 + AK 4,757,256 Whann et al. 324 158 P 5/1/87 FOREIGN PATENT DOCUMENTS No. Document No. Date Country Class Sub-Trans-Class lation 2 680 284 2/12/93 France No AM 61287254 12/17/86 Japan (Abstract) AN 61244057 10/30/86 Japan (Abstract) AO WO 96/02959 2/1/96 WIPO 1 026 876 3/27/58 Germany No OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) U. Renz, "Multipoint Test Probe for Printed Cards", IBM Technical Disclosure Bulletin, Vol. 17, No. 2, July 1974, pp. 2 pgs. total. "Chip Column Package Structure", IBM Technical Disclosure Bulletin, Vol. 40, No. 08, August 1997, pp. 117-118. Alan D. Knight, "MCM-TO-PRINTED WIRING BOARD (SECOND LEVEL) CONNECTION TECHNOLOGY OPTIONS", pp. 487-523. Examiner Date Considered EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not consid red. Include copy of this form with next communication to applicant.

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Form PTØ-1449 (Modified) S rial No.: 09/295,269 Atty Docket N .: 003401.P002D7D1 JUL 17 2002 6 List of Paters and Publications Statement Applicant: Igor Y. Khandros (Use several sharp necessary) Filing Date: April 20, 1999 Page 3 of 5 REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS** Document No. Class Sub-Filing date Examiner Class if appropriate Initials Miyazaki et al. 364 551.01 8/6/86 AA 4,780,836 339 17 M 1/22/85 Anhalt et al. AB 4,634,199 324 158 P 5/21/81 AC 4,523,144 Okubo et al. 361 395 8/25/83 AD 4,553,192 Babuka et al. 29 628 12/11/72 Luttmer ΑE 3,795,037 702 257 10/28/92 AF 5,350,947 Takekawa et al. 357 68 4/27/84 AG 4,667,219 Lee et al. arrad 357 1/24/91 AH 5,067,007 Kanji et al. 74-324 158 F 2/15/91 ΑI 5,157,325 Murphy 324 12/9/91 -158 F Goto AJ 5,218,292 5,399,982 Driller et al. 324 754 5/4/93 AK **FOREIGN PATENT DOCUMENTS** Class Sub-Trans-Document No. Date Country No. lation Class No 3-142847 (A) 6/18/91 Japan No 15/11/79 Japan AM 54-146581 No 56-26446 (A) 3/14/81 Japan AN 0 500 074 A1 8/26/92 Europe ΑO 0 614 089 A2 9/7/94 Europe OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) Beaman et al., "ELASTOMERIC CONNECTOR FOR MCM AND TEST APPLICATIONS", AR ICEMM Proceedings '93, pp. 341-346. "Cooling System for Semiconductor Modules", IBM Technical Disclosure Bulletin, August 1983, AS pp. 2 pgs. total. "Method of Testing Chips and Joining Chips to Substrates", Research Disclosure, February AT 1991, No. 322, pp. 1. **Date Considered** Examiner EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.





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